

Core Structure of Dissociated Dislocations in Bi_2Te_3

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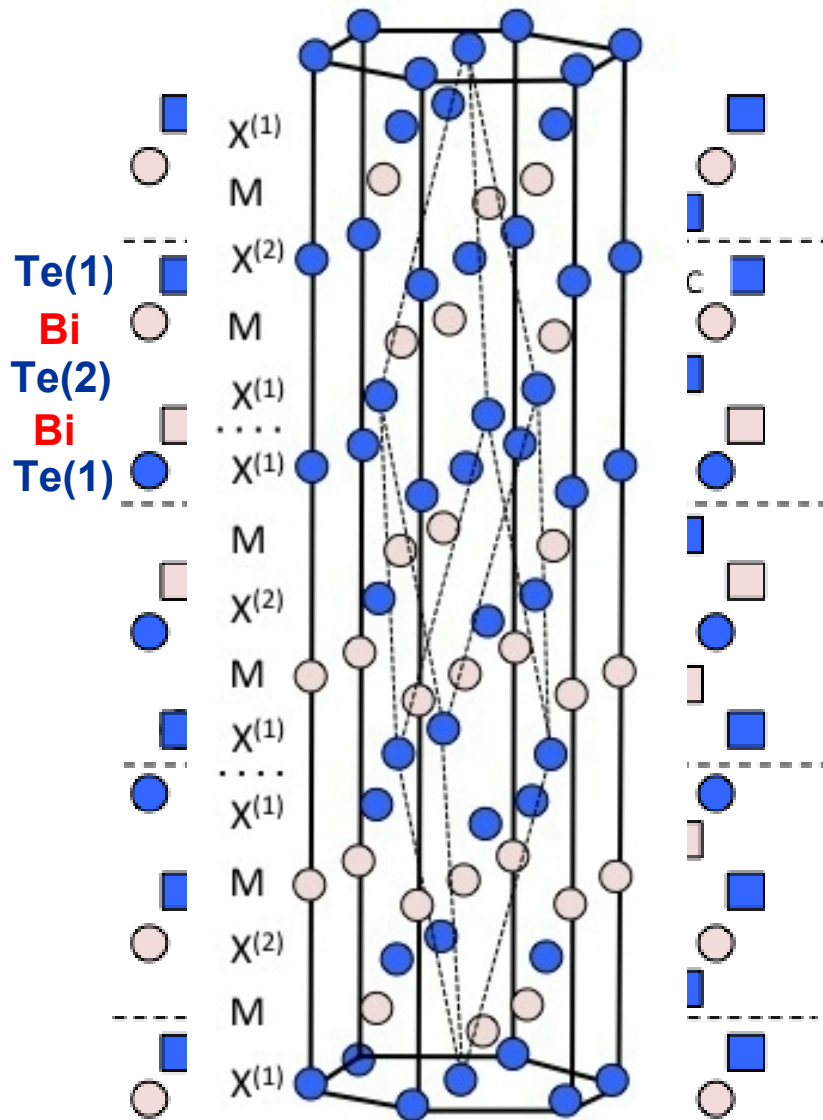
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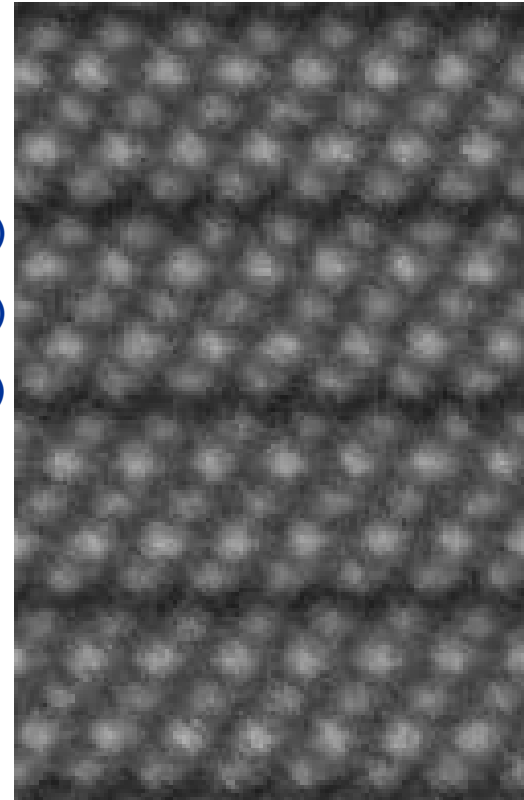
Bismuth Telluride (Bi_2Te_3): Crystal Structure



- Rhombohedral ($R\text{-}3m$) structure
- Based on tetradymite (Bi_2STe_2) prototype
- Three crystallographically distinct atomic sites
- $\text{Te}^{(1)}\text{-Te}^{(1)}$ layers: van der Waals bonding

HAADF-STEM

Te(1)
Bi
Te(2)
Bi
Te(1)



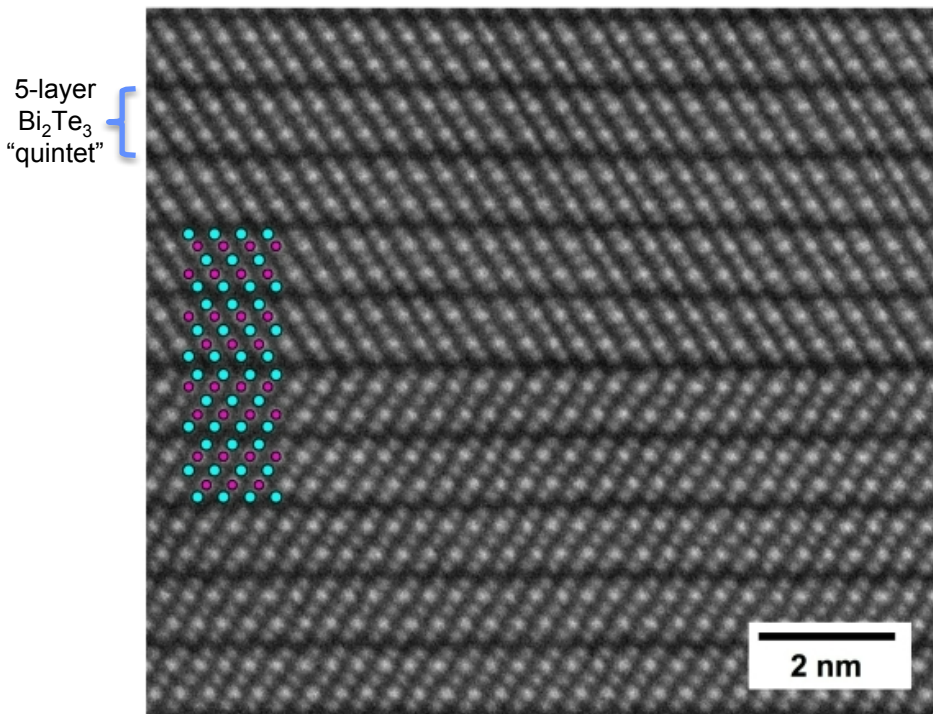
Bi: $Z=83$
Te: $Z=52$

Atomic number
difference enables
Bi and Te to be
distinguished in
HAADF-STEM

Atomic Structure of the Bi_2Te_3 Basal Twin: Energetic preference for termination at $\text{Te}^{(1)}$ sites

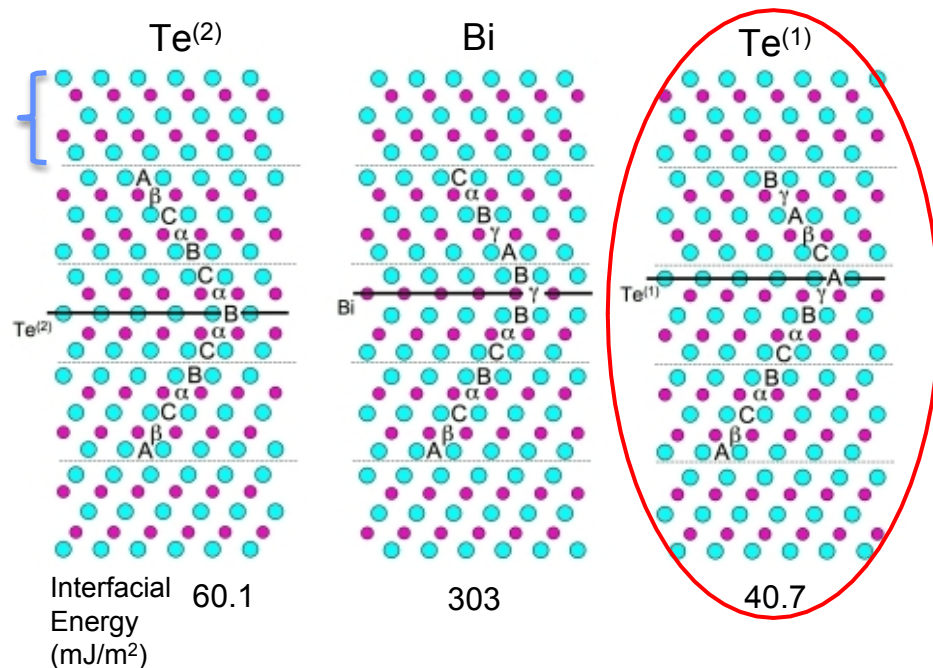
HAADF-STEM Imaging:

Twin Boundary Terminated at $\text{Te}^{(1)}$ layer



DFT Calculations:

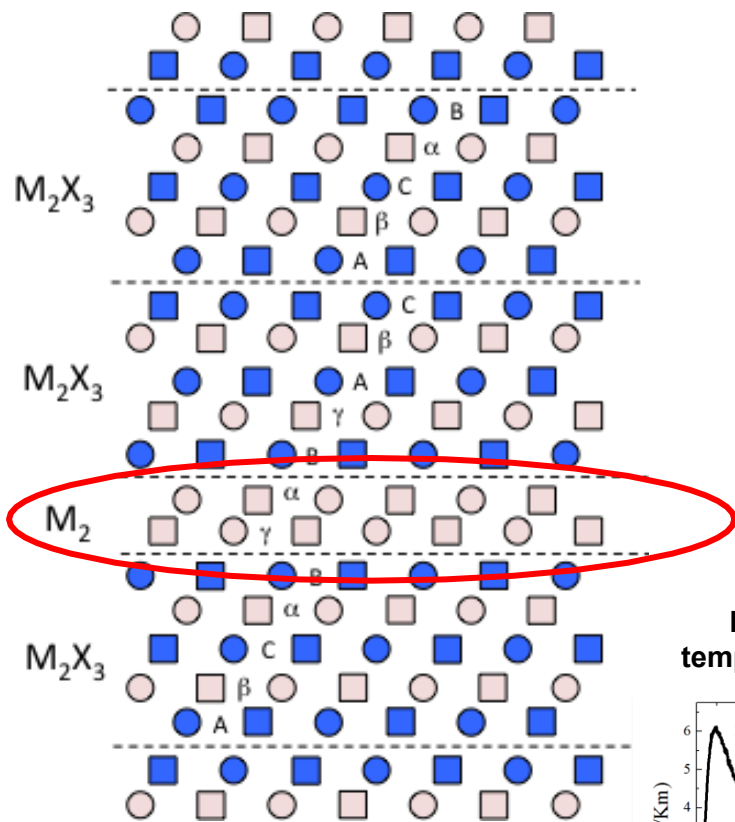
Three Possible Compositional Terminations



D.L. Medlin, Q.M. Ramasse, C. D. Spataru, N.C. Yang, J. Appl. Phys. (2010)

Layered structure allows flexibility in accommodating variations in composition

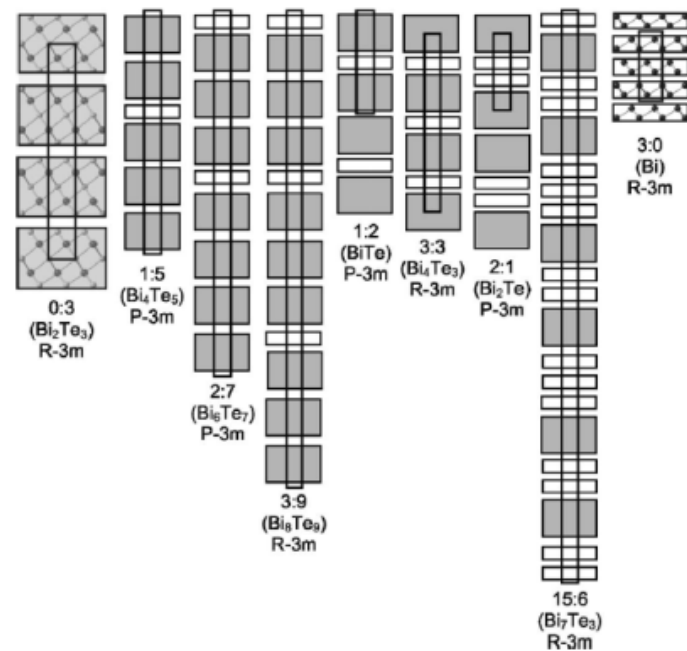
Insertion of metal bi-layers



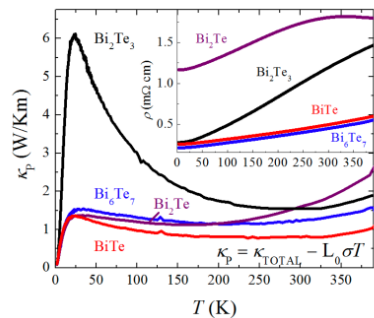
Example:
 $(Bi_2)_m(Bi_2Te_3)_n$
 homologous series

J.W.G. Bos, H.W. Zanderbergen,
 M.-H. Lee, N.P. Ong,
 R.J. Cava,
 Phys. Rev B 2007

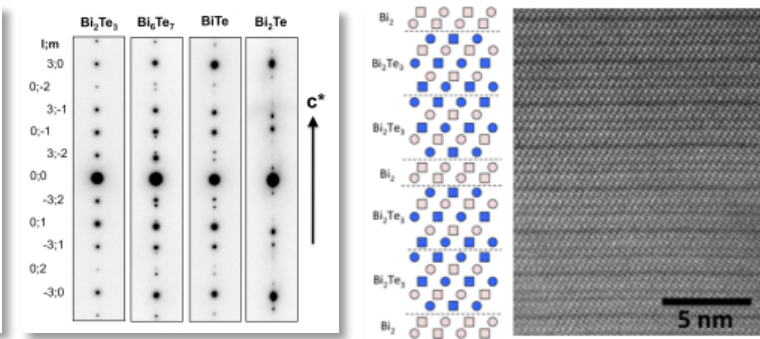
Increasing Bismuth →



Dramatic reduction in low-temperature thermal conductivity

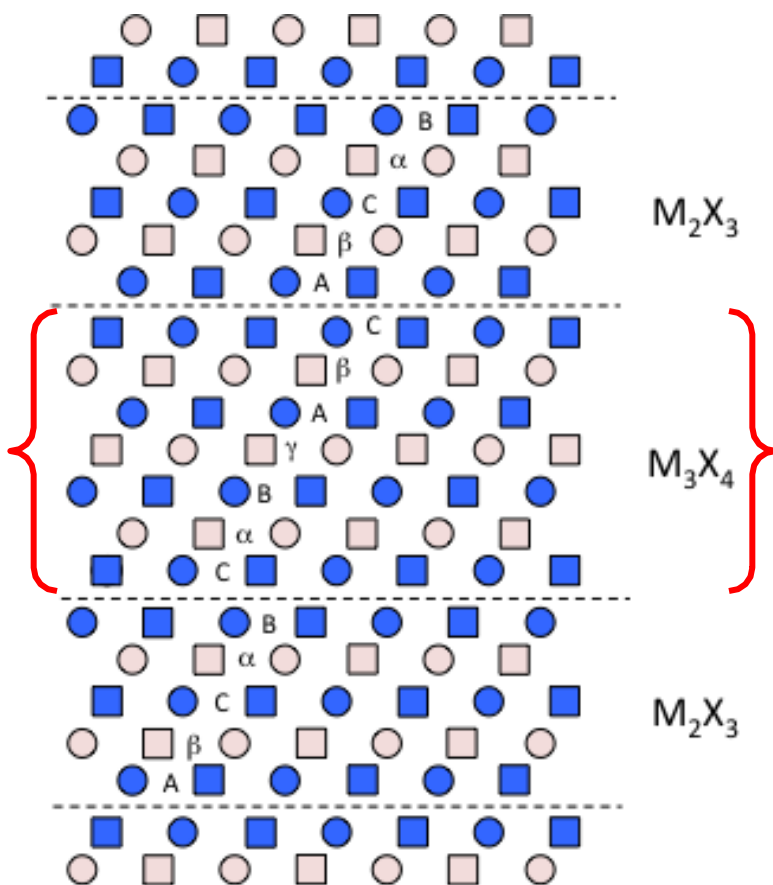


Electron diffraction and HRSTEM show ordering in $(Bi_2)_m(Bi_2Te_3)_n$ series

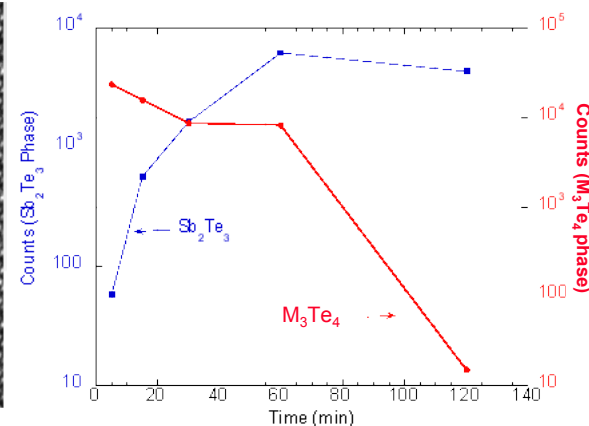
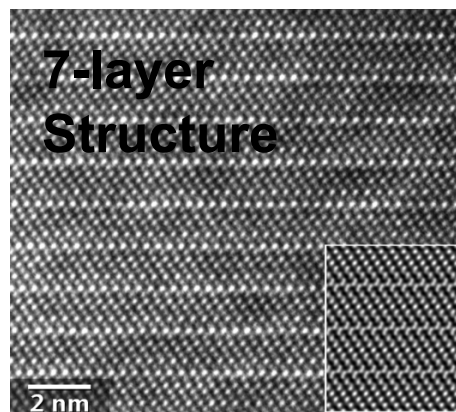
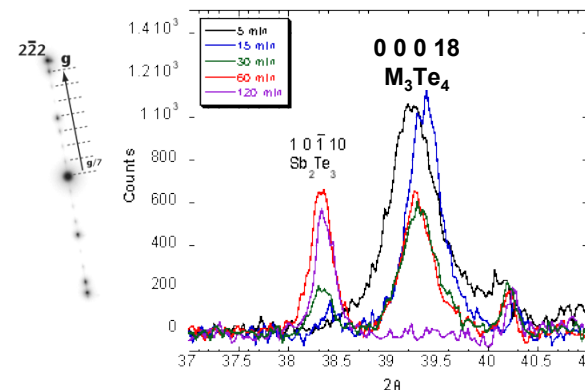
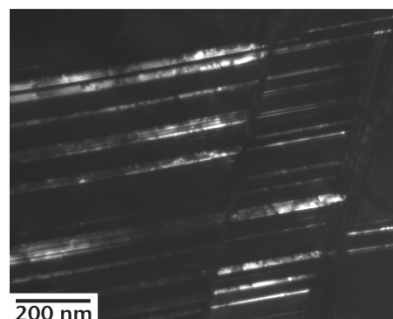


Layered structure allows flexibility in accommodating variations in composition

Metal rich, 7-Layer M_3X_4 fault



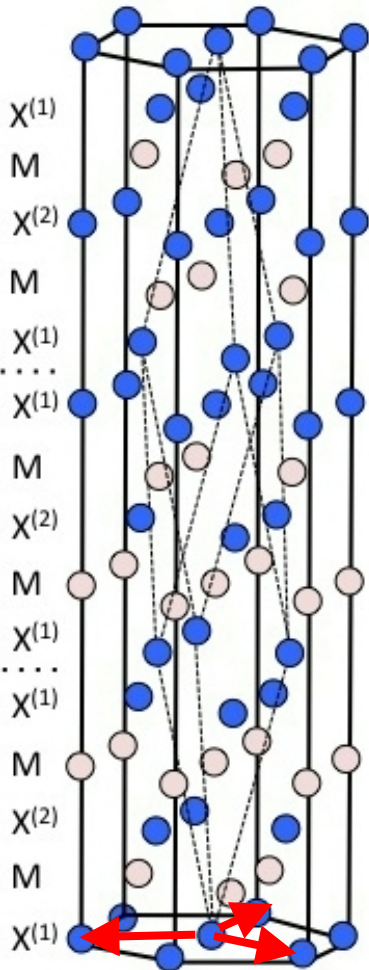
Example: $(Ag,Sb)_3Te_4$ transition phase during nucleation of Sb_2Te_3 precipitates in $AgSbTe_2$



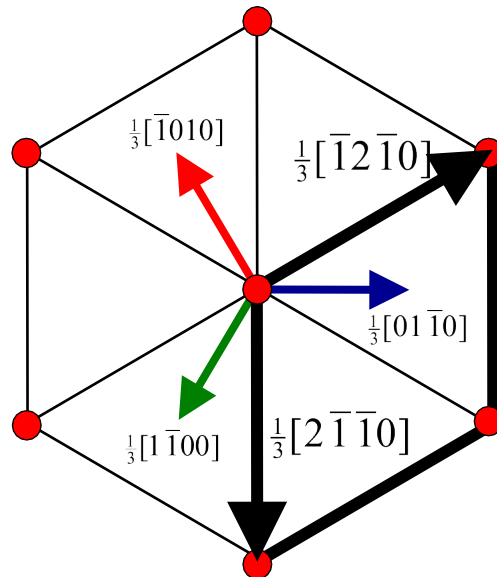
Sharma, Sugar, & Medlin, Journal of Applied Physics (2010).
Sugar and Medlin, Journal of Materials Science (2011)

Dislocations in Bismuth Telluride

Burgers vectors lying in basal plane



Looking down on basal plane



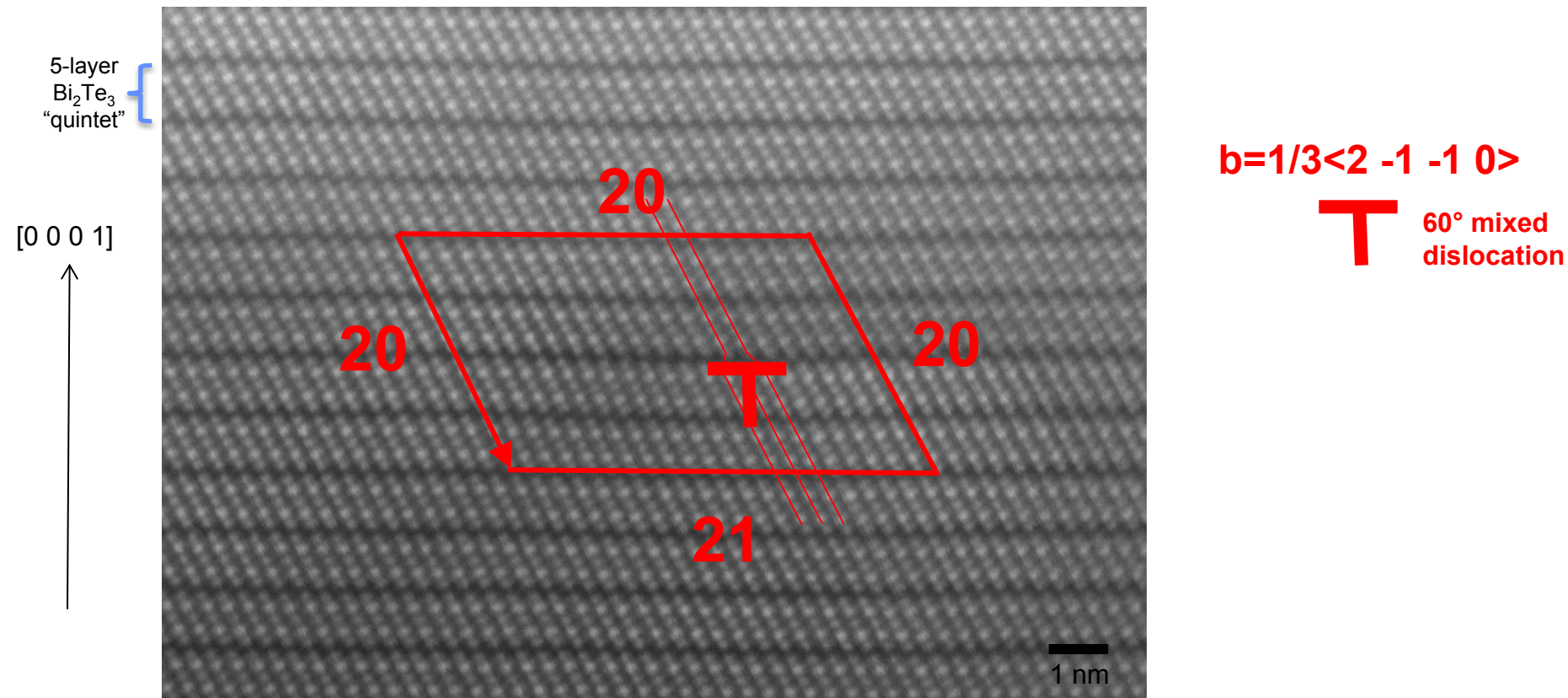
Array of $\frac{1}{3}\langle 2-1-1\ 0 \rangle$ Dislocations in Bi₂Te₃

Amelinckx and Delavignette, 1960



Fig. 1. Dislocation network in Bi₂Te₃. Note that certain segments of dislocations and certain node-points have left the foil

Dislocation Core structure: termination at $\text{Te}^{(1)}\text{-Te}^{(1)}$ layer, dissociation

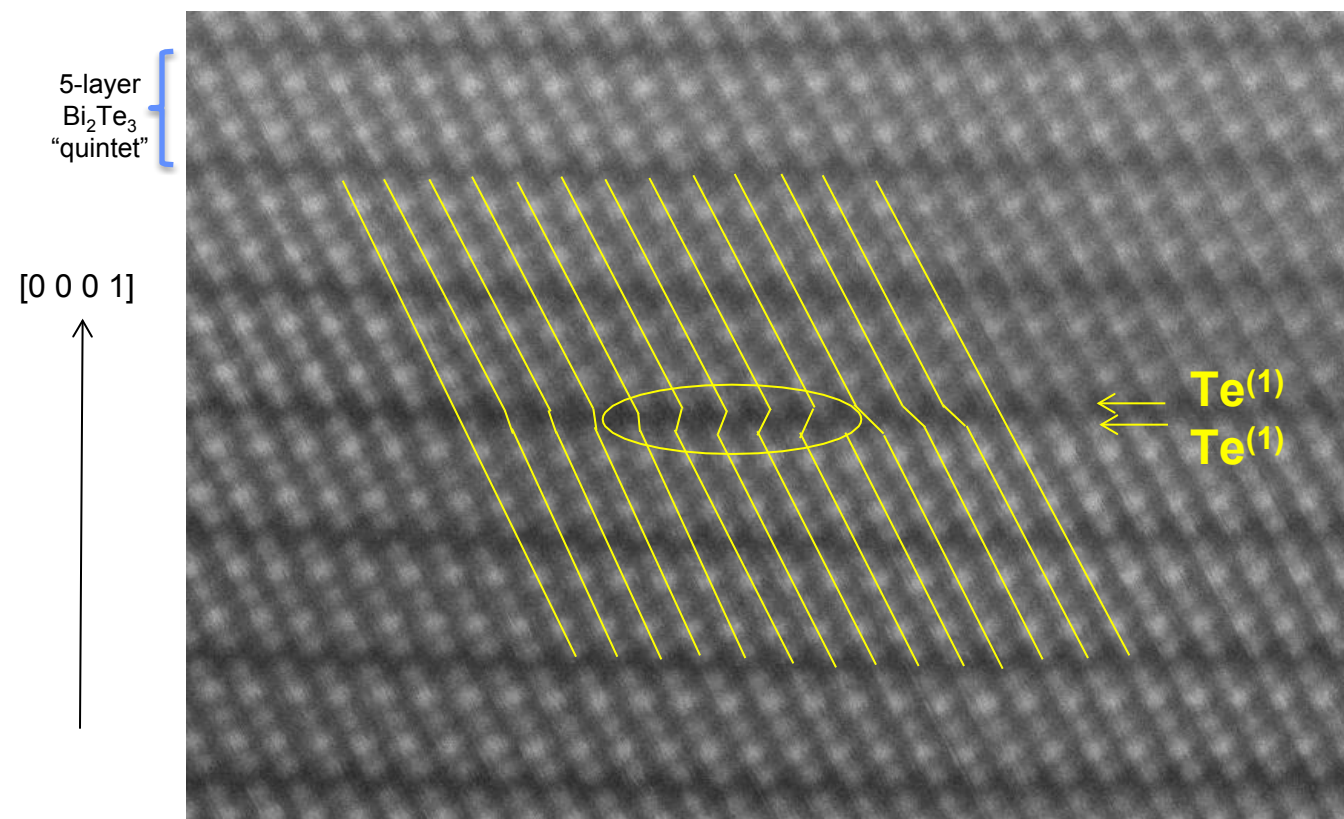


FEI-Titan
HAADF-STEM
300 keV

$\langle 2\ -1\ -1\ 0 \rangle$ projection

Bulk Bi_2Te_3
Hot Extruded

Dislocation Core structure: termination at $\text{Te}^{(1)}\text{-Te}^{(1)}$ layer, dissociation



$$b = \frac{1}{3} \langle 2 \ -1 \ -1 \ 0 \rangle$$



60° mixed
dislocation



30° mixed
partial

Stacking
Fault



90° edge
partial

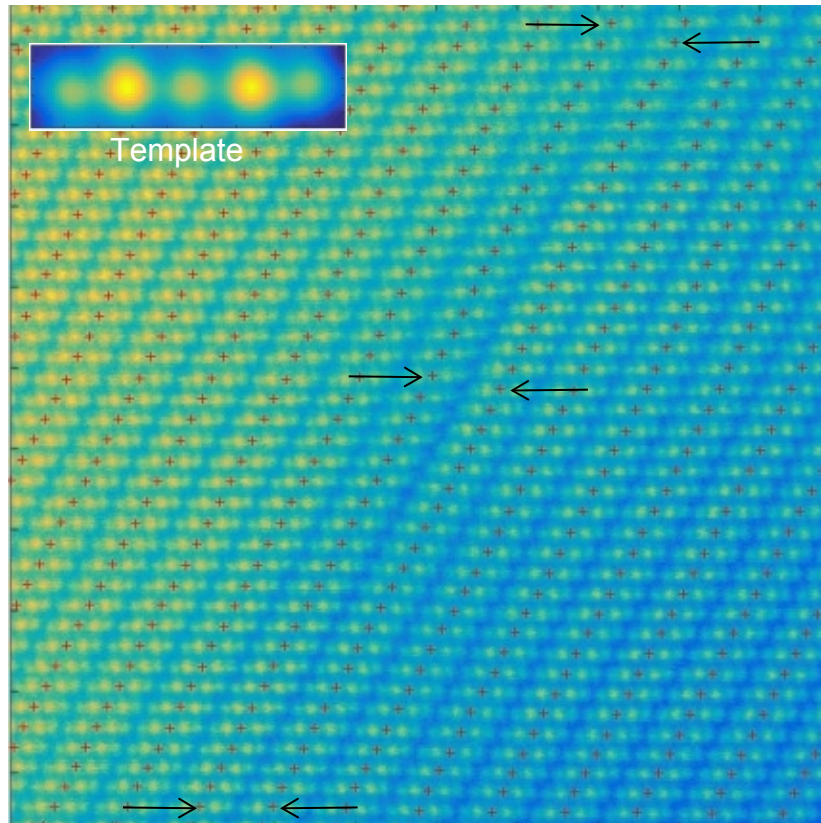
$\frac{1}{3} \langle 1 \ 0 \ -1 \ 0 \rangle$ partial
dislocations.

FEI-Titan
HAADF-STEM
300 keV

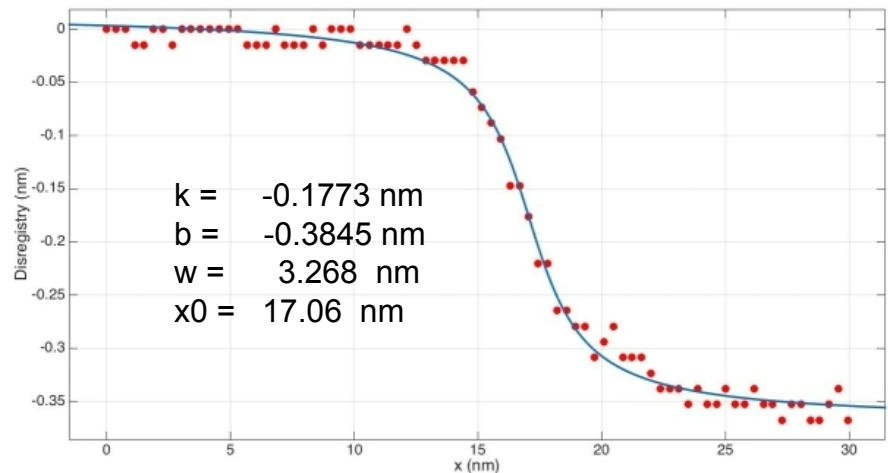
Weak, van der Waals bonding likely
favors dissociated dislocation core
at $\text{Te}^{(1)}\text{-Te}^{(1)}$ layer

Quantify Disregistry on Slip Plane using Peierls-Nabarro Dislocation Model

Disregistry of $\{1\ 0\ -1\ 5\}$ planes across slip plane measured through template matching



$$\underbrace{u_+ - u_-}_{\text{Disregistry}} = \underbrace{k}_{\text{Burgers vector}} + \frac{b_{edge}}{\pi} \tan^{-1} \left(\frac{x - x_0}{\underbrace{w/2}_{\text{core-width}}} \right)$$



$w = 3.7 \text{ nm} \pm 0.6 \text{ nm}$

6 dislocations
2-4 measurements each



$\mu \sim 25.6 \text{ GPa}$
 $\nu \sim 0.26$

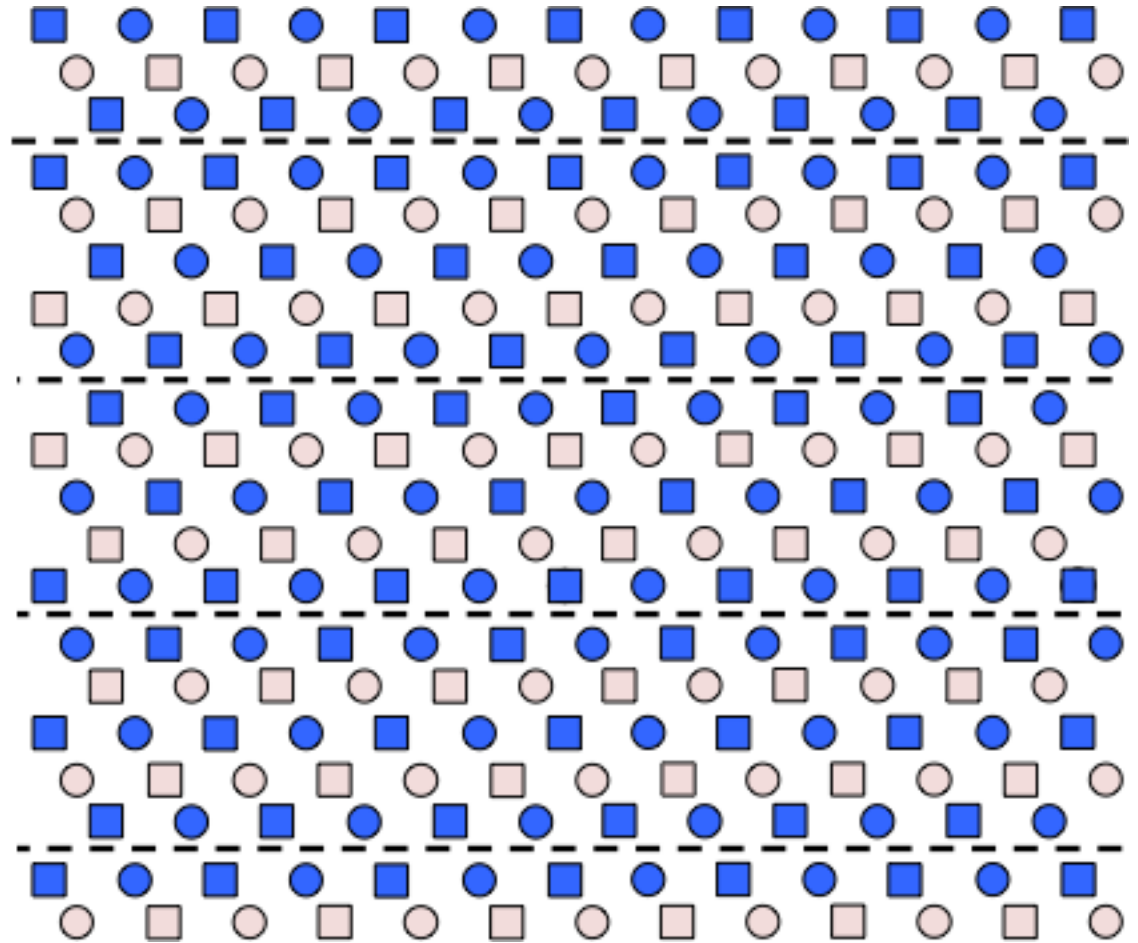
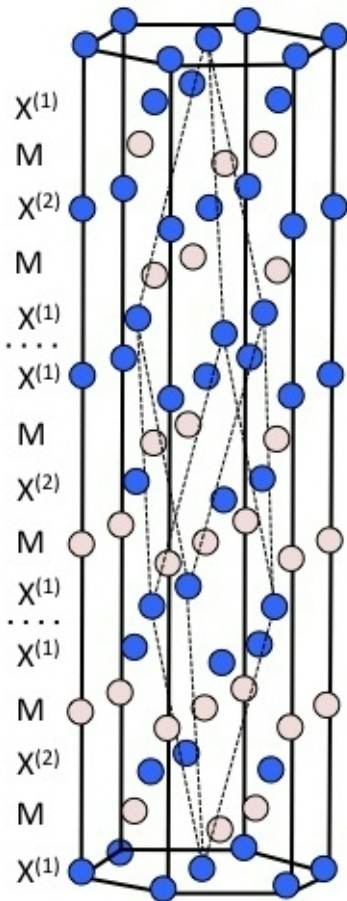
Estimate stacking fault energy

SFE = $147 \pm 23 \text{ mJ/m}^2$

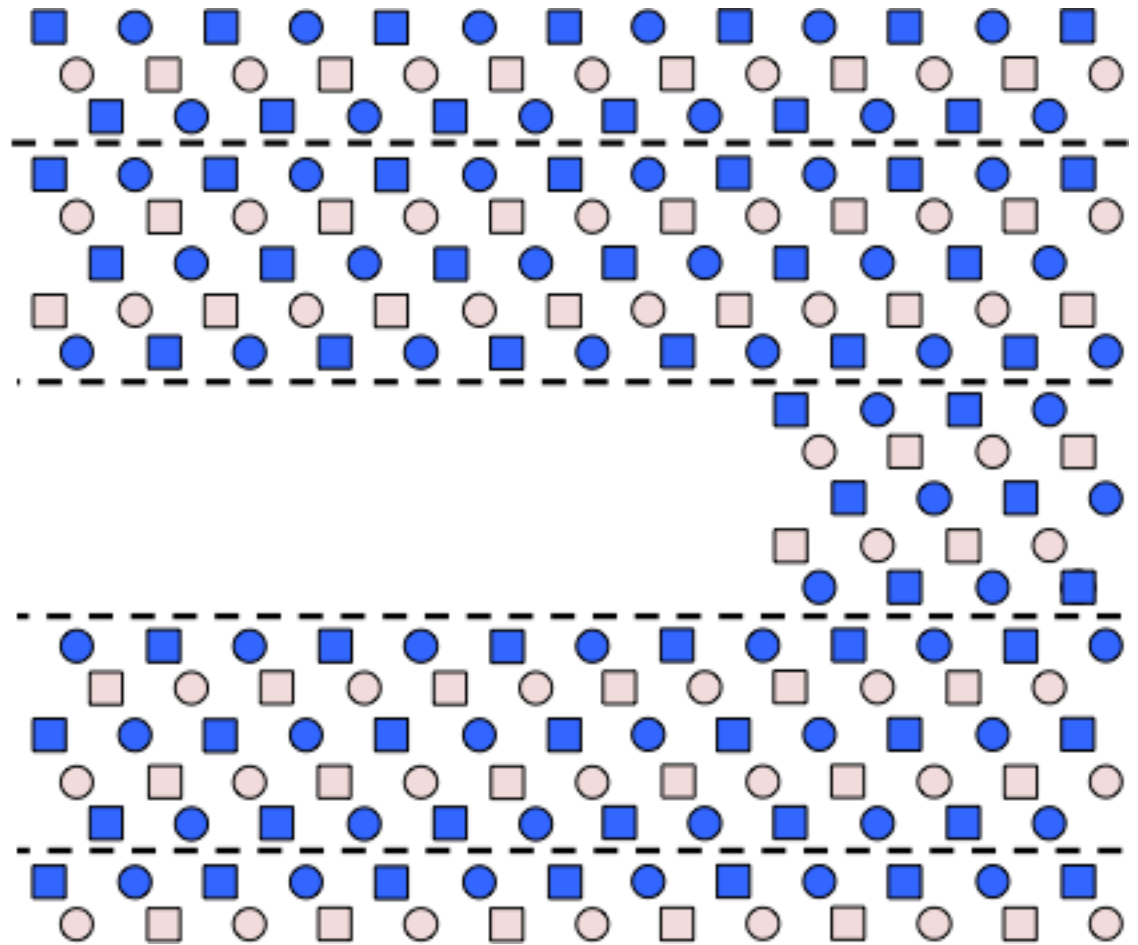
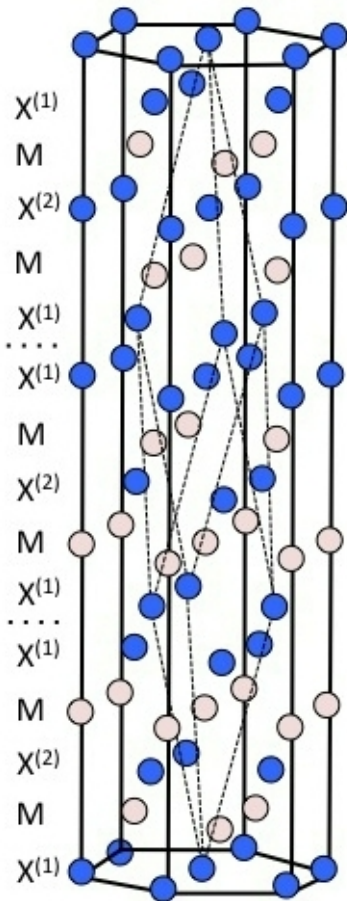
(c.f., DFT for basal twin: 41 mJ/m^2)

Non-basal dislocations:

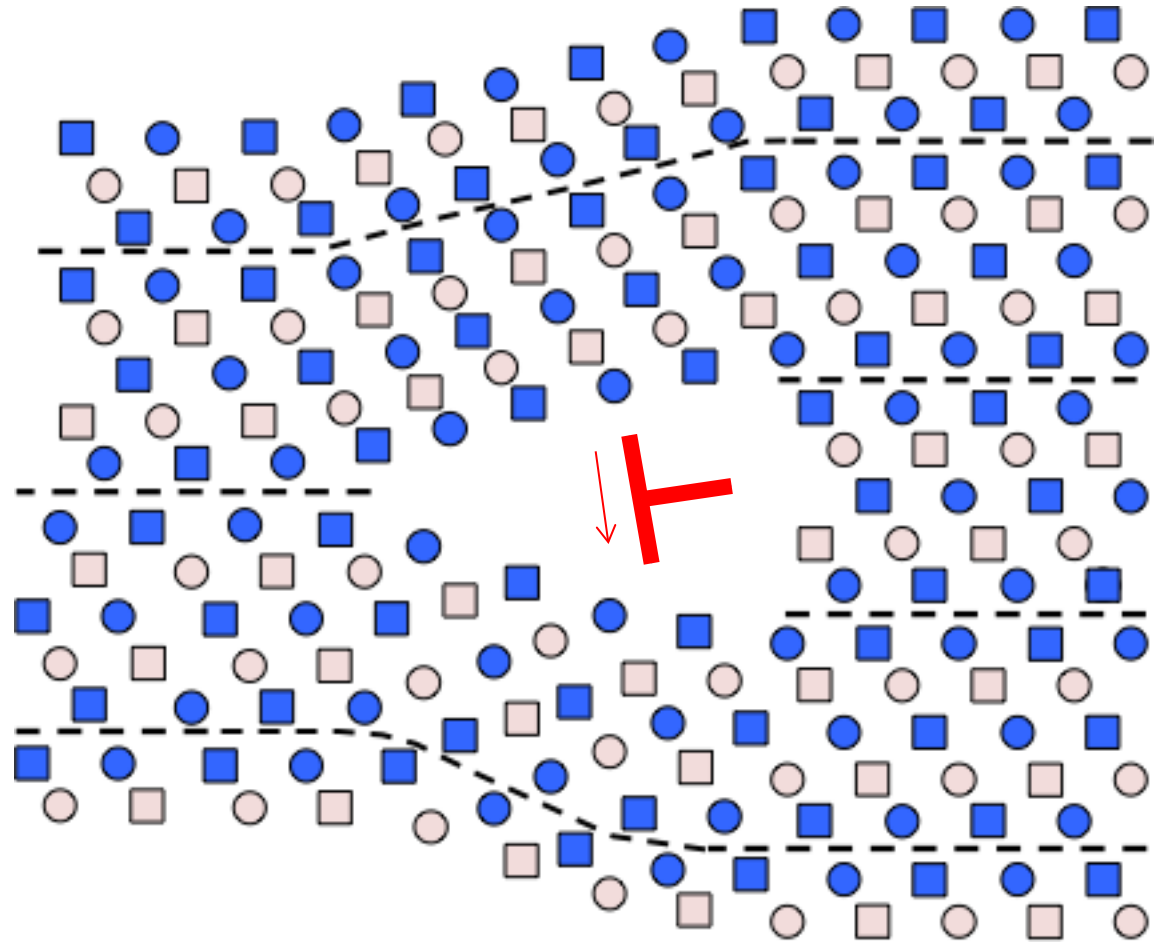
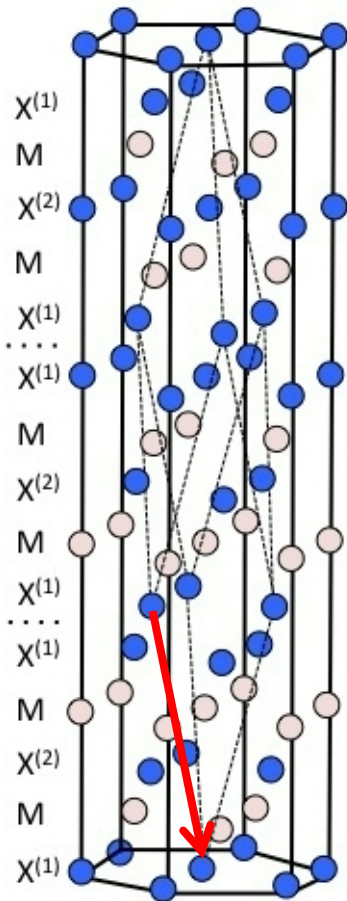
What happens if we pull out a quintuple unit?



Non-basal dislocations: What happens if we pull out a quintuple unit?

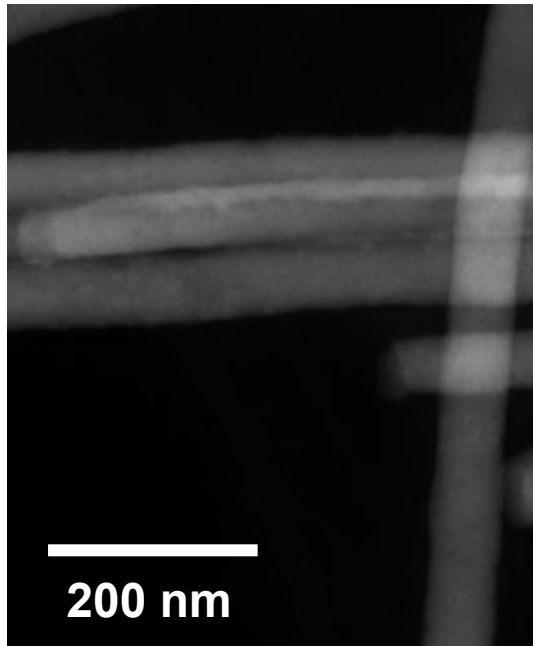


Non-basal dislocations: What happens if we pull out a quintuple unit?



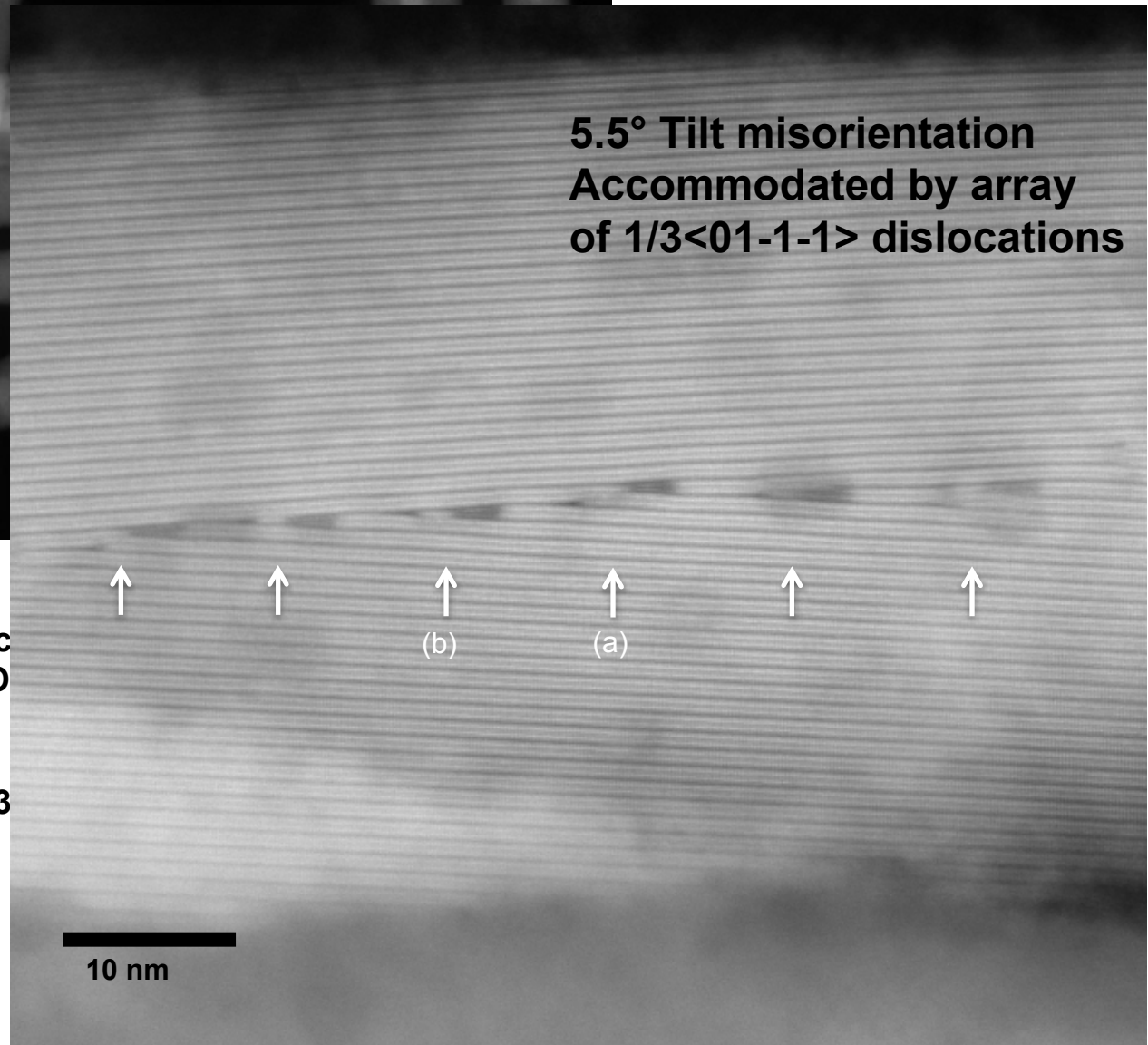
$$b = (1/3)[01-1-1]_H = [00-1]_R$$

Dislocations in Bi_2Te_3 Nanowires

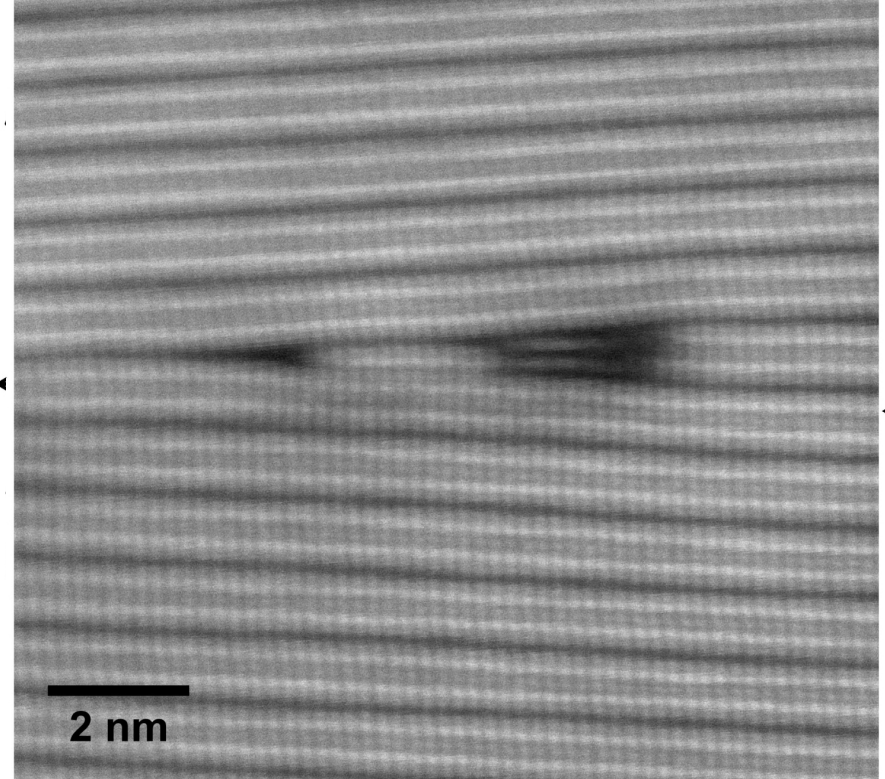
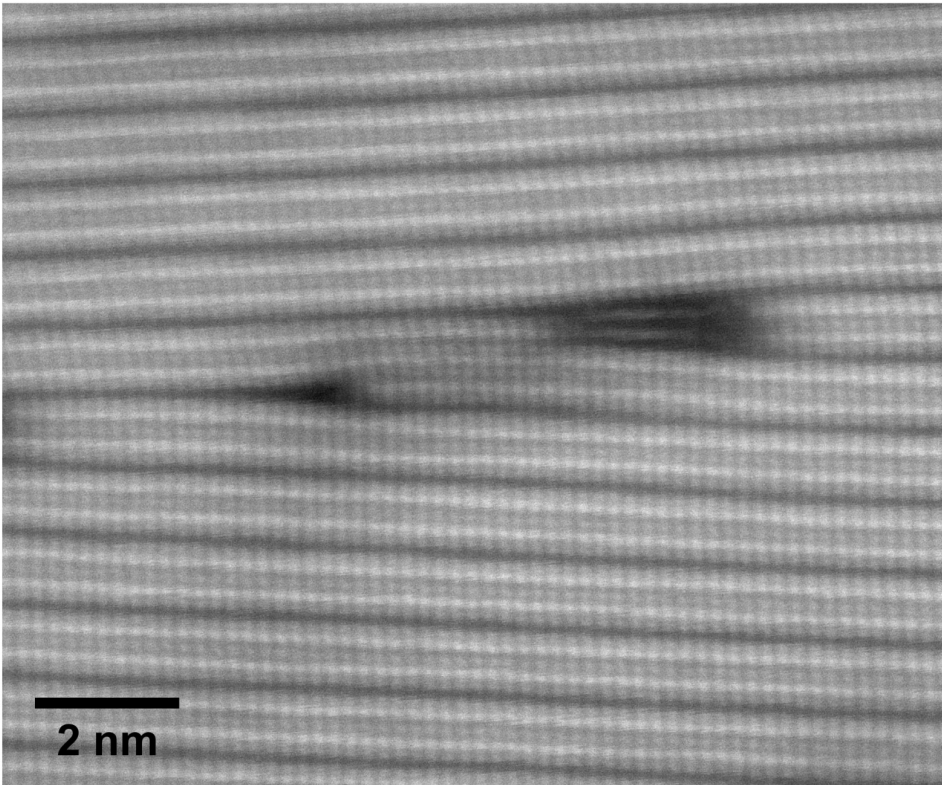


Wires formed by electrochemical deposition in nanoporous AAO templates.

Free standing wires annealed 3 minutes at 300°C in Ar-3%H₂.

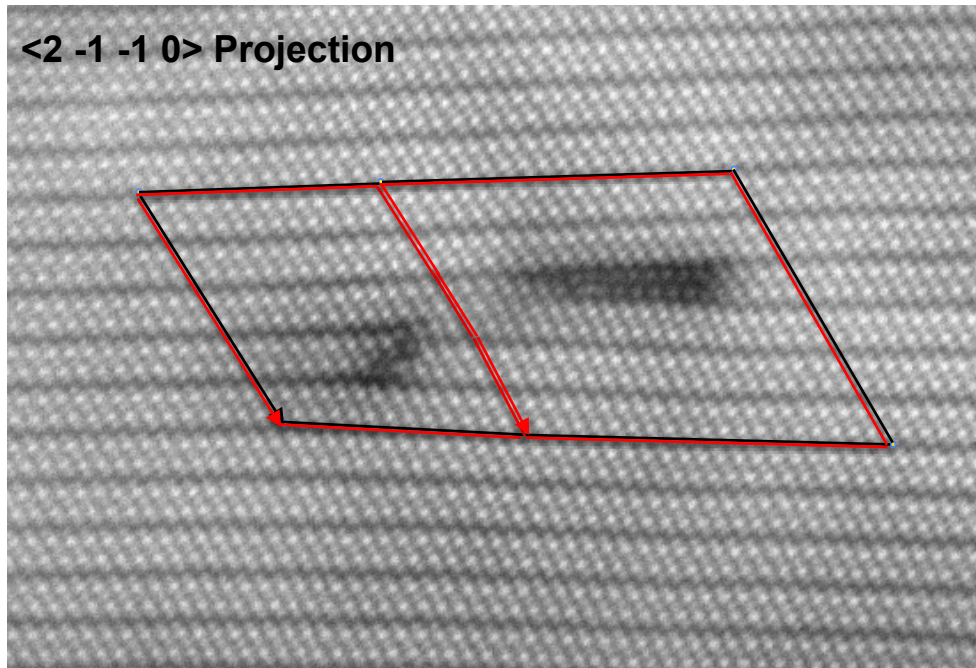


Dislocations have dissociated core: two configurations

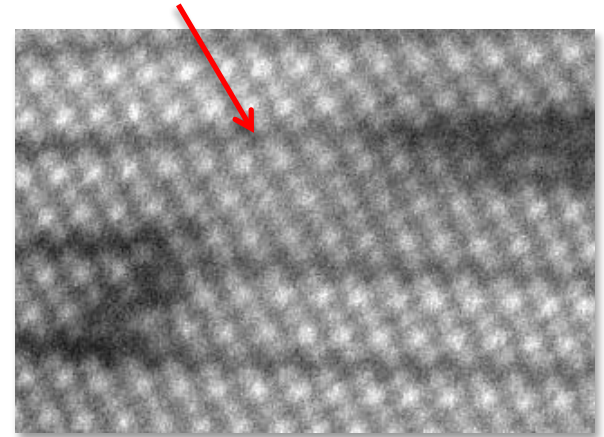


$\langle 1\ 0\ -1\ 0 \rangle$ Projection

$(1/3)[0\ 1\ -1\ -1]$ Dislocation in Bi_2Te_3 :



Core structure:
 Bi_3Te_4 7-layer fault



$$\mathbf{b} = (1/3) [0\ 1\ -1\ -1] \rightarrow (1/15) [0\ 5\ -5\ -2] + (3/15) [0\ 0\ 0\ -1]$$

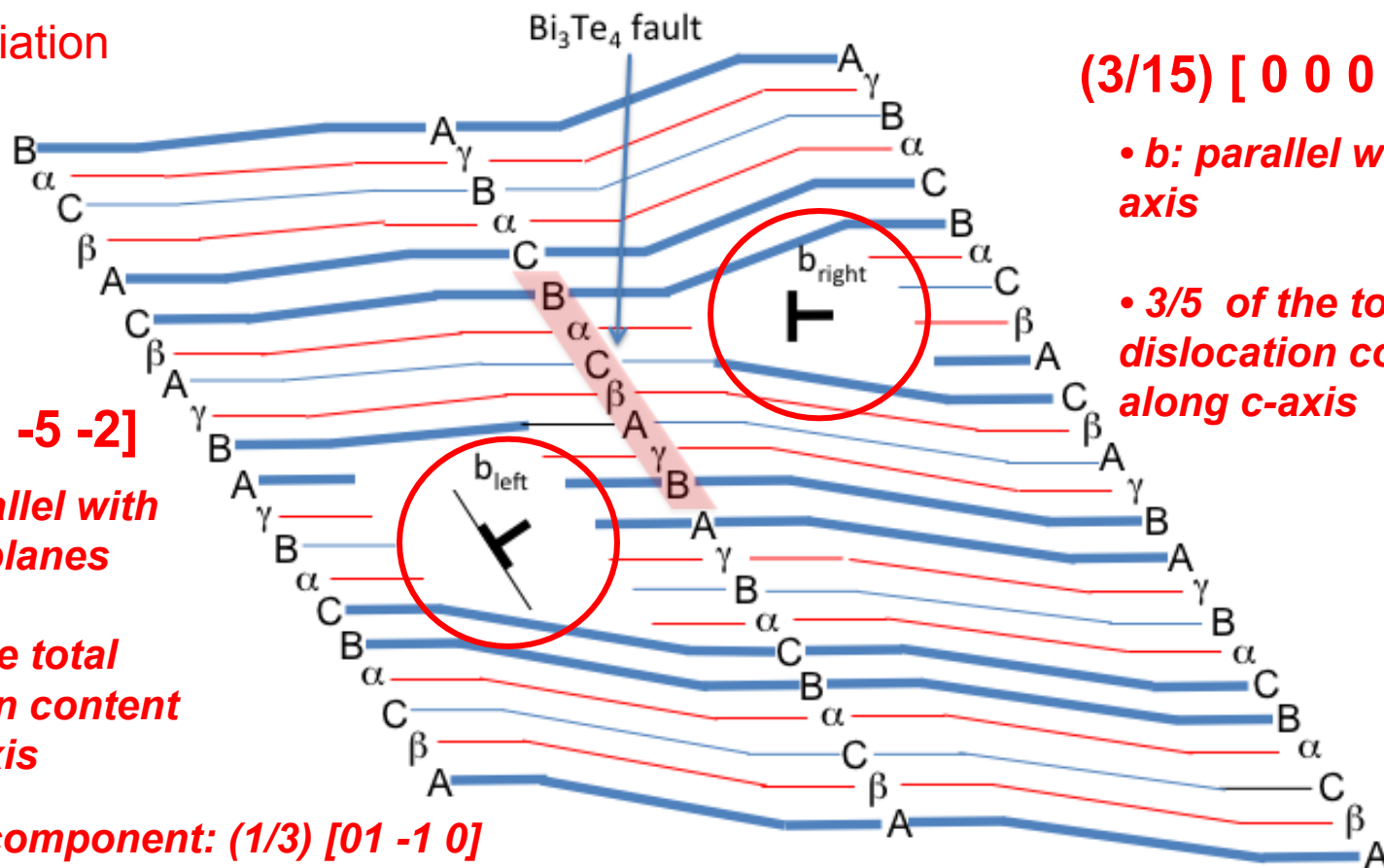
$$b^2 > b_1^2 + b_2^2$$

$$109.8\ \text{\AA}^2 > 22.9\ \text{\AA}^2 + 37.2\ \text{\AA}^2 = 60.2\ \text{\AA}^2$$

Reduced strain energy with dissociation

7-Layer Bi_3Te_4 faults: Mechanism to accommodate Te loss during annealing

Climb dissociation



$(1/15) [0\ 5\ -5\ -2]$

- b is parallel with $(0\ 1\ -1\ 5)$ planes
- $2/5$ of the total dislocation content along c -axis

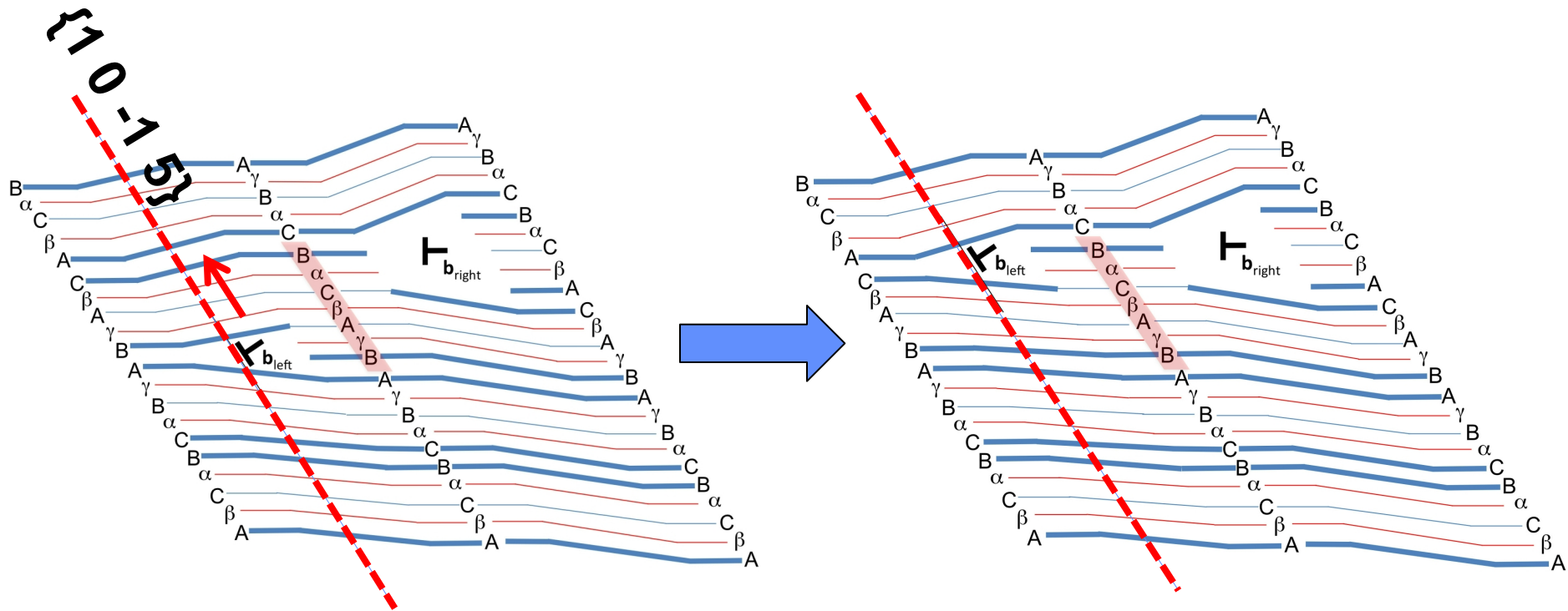
Horizontal component: $(1/3) [01\ -1\ 0]$

- analogous to Shockley partial.
- avoids fault in stacking resulting from additional 2 planes at Bi_3Te_4 fault

$(3/15) [0\ 0\ 0\ -1]$

- b : parallel with c -axis
- $3/5$ of the total dislocation content along c -axis

Core can re-configure via glide of the left partial dislocation on $\{1\ 0\ -1\ 5\}$ plane



- $\{1\ 0\ -1\ 5\}$ is densely packed plane in tetradymite structure
- Analogous to $\{001\}$ plane in rock-salt structure.

Conclusions

- We have investigated the core-structures of two types of dislocation in Bi_2Te_3 .

$(1/3)\langle 2 \ -1 \ -1 \ 0 \rangle$ (basal dislocation)

- Defect terminates at Te(1)-Te(1) layer, allowing for stoichiometric core.
- Weak dissociation on basal plane

$(1/3)\langle 0 \ -1 \ 1 \ 1 \rangle$ type dislocation

- Large Burgers vector component along the c-axis accommodates misorientations at low angle grain boundaries vicinal to (0001).

-Dissociated core structure:

Local 7-layer defect region consistent with single, septuple unit of Bi_3Te_4

Formation of partial dislocations is favorable from strain energy considerations.

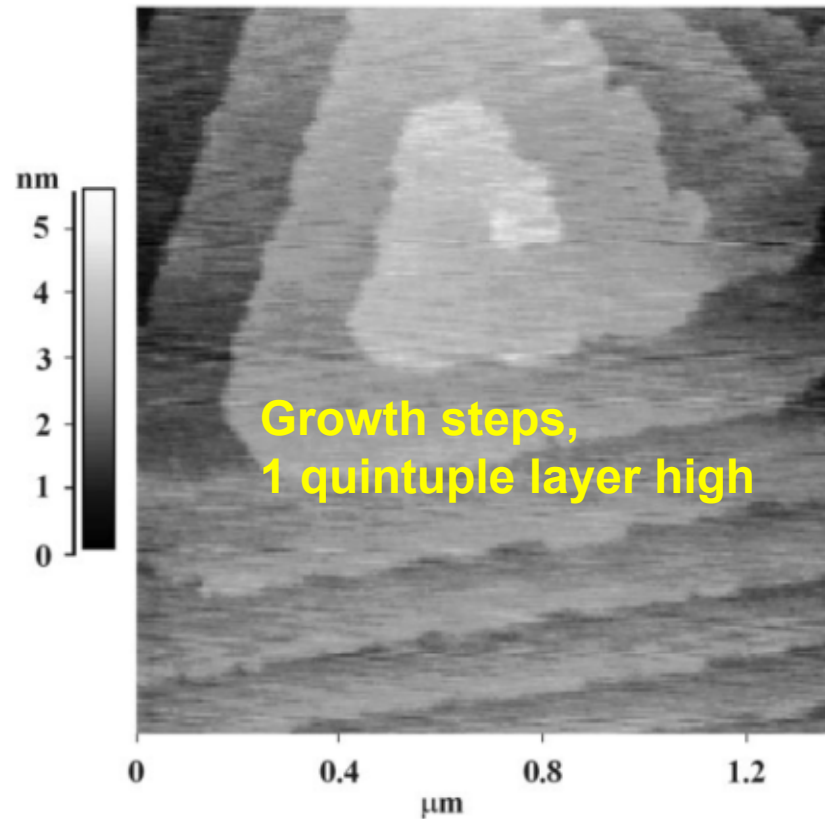
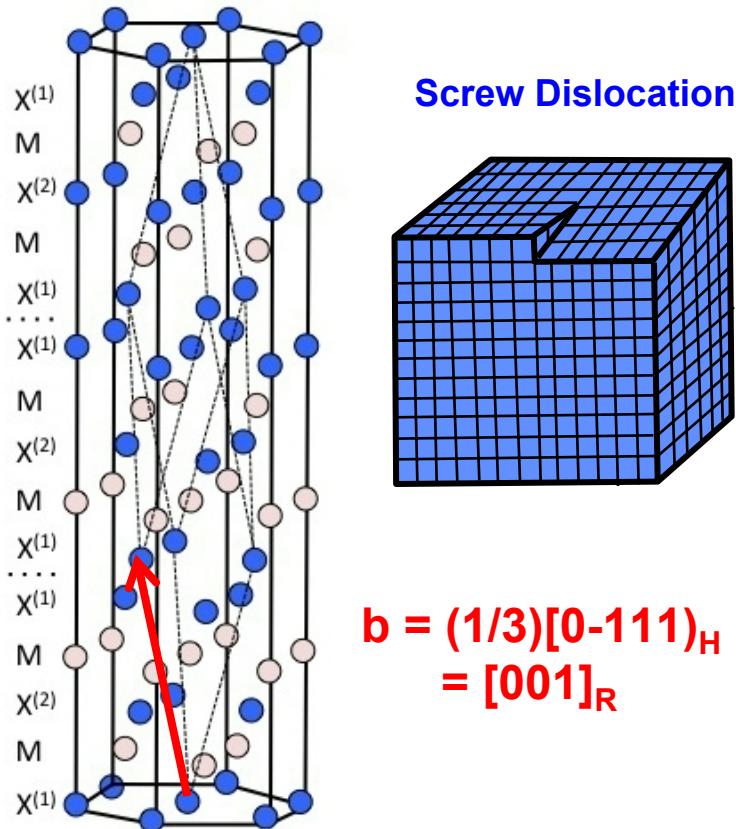
7-layer defect provides a mechanism for accommodating tellurium deficiency.

EXTRA

Non-basal dislocations:

Screw dislocations important to crystal growth

Example: spiral growth steps at screw dislocation in Bi_2Te_3 thin film

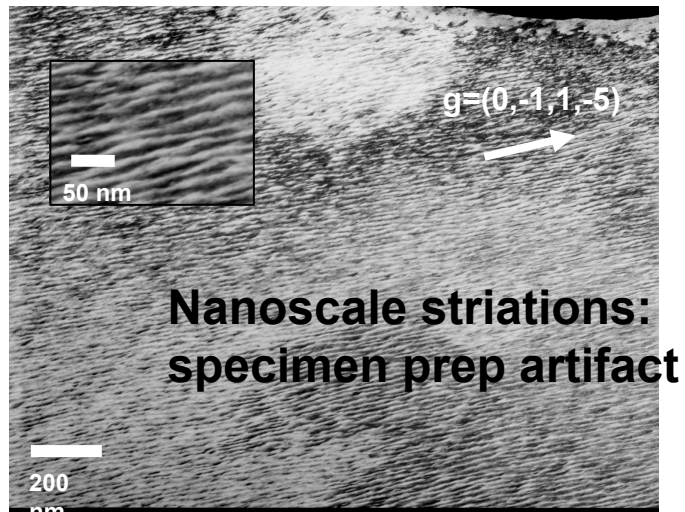


What about **edge** dislocations
with non-basal Burgers vectors?

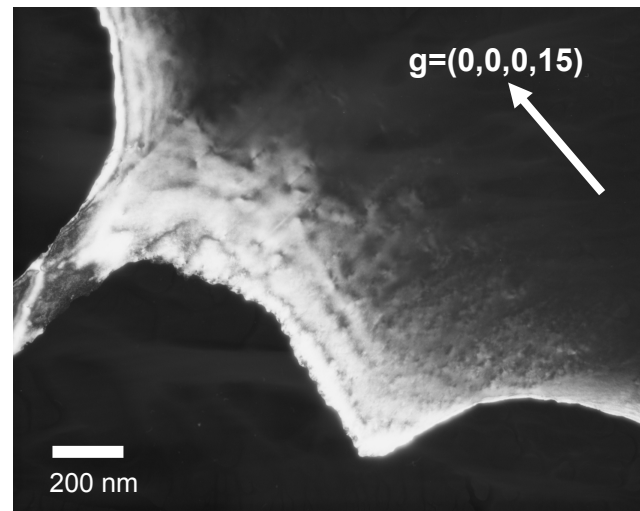
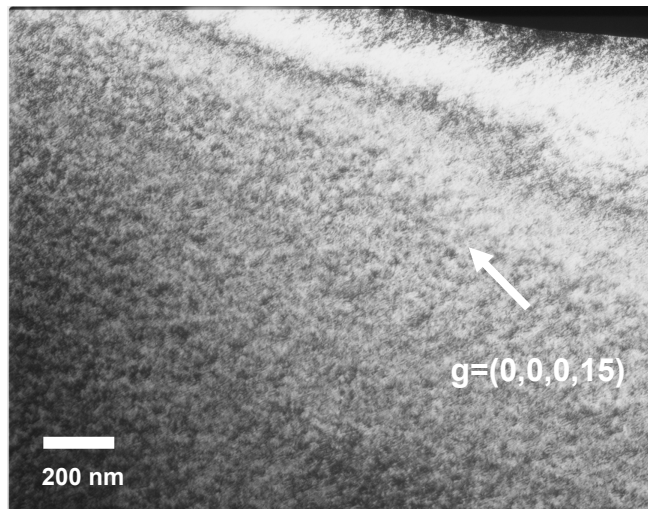
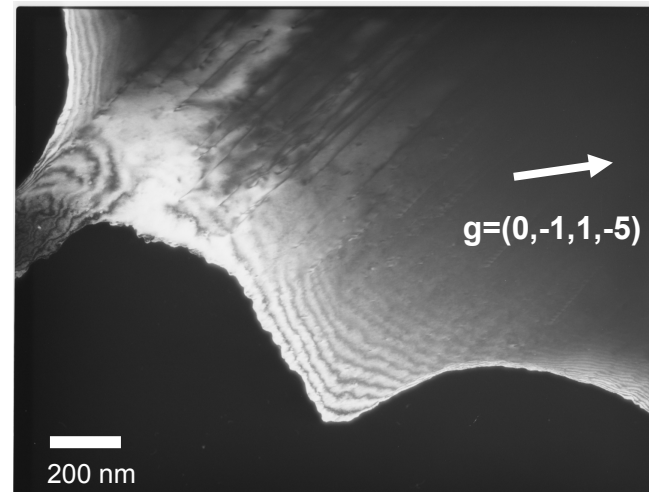
M. Ferhat, J.C. Tedenac, J. Nagao,
J. Crystal Growth (2000)

Aggressive ion-milling produces nanoscale artifacts in Bi_2Te_3

Ion Milled (Gatan DualMill 5 kV Ar+)



Electrochemical Polish



Can avoid artifacts using low-voltage, low-angle ion milling with cryo-cooling